

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-038001	Application No. Not Assigned Yet
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)		Applicant Hideomi Suzawa et al.	
		Filing Date May 11, 2001	Group Art Unit Unknown

(37 CFR §1.98(b))

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09/852672  
05/11/01

### U.S. Patent Documents

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	6,030,667	2/29/2000	Nakagawa et al.			
	AB						
	AC						
	AD						
	AE						
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	AG						
	AH						
	AI						
	AJ						
	AK						

### Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL	JP9293600	11-11-1997	Japan				
	AM							
	AN							
	AO							
	AP							

### Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature 	Date Considered 6/12/02
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Patent and Trademark OfficeAttorney's Docket No.  
12732-038001Application No.  
09/852,672**Information Disclosure Statement  
by Applicant**

(Use several sheets if necessary)

Applicant  
Hideomi Suzawa et al.Filing Date  
May 11, 2001Group Art Unit  
2812**U.S. Patent Documents**

Examiner Initial	Desig. ID	Patent/Application Number	Issue Date	Patentee	Publication No.	Filing Date
<i>B</i>	AA	09/841,537	Pending	Yamazaki et al.	US 2001/0035526 A1	04/24/2001
<i>B</i>	AB	09/852,282	Pending	Suzawa et al.	US 2002/0006705 A1	05/10/2001
<i>B</i>	AC	09/615,449	Pending	Suzawa et al.	Pending	07/13/2000
<i>B</i>	AD	09/769,765	Pending	Yamazaki et al.	Pending	01/26/2001
	AE					
	AF					
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	AH					
	AI					

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	AL							
	AM							
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	AP	
	AQ	
	AR	

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Date Considered

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